

Search Notes

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EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

OKAHARA ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

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264/328.7,255,250,328.8 ,328.11		8/28/2010	EHL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
UPDATED	8/28/2010	EHL
EAST	8/28/2010	EHL
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